

PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER	
NOMINAL FREQUENCY	32.768 KHz
PRODUCT TYPE	TYPE G8 SMD CRYSTAL
SPEC. NO. (P/N)	G83270022
CUSTOMER P/N	
ISSUE DATE	Jun.16,2016
VERSION	Α

APPROVED	PREPARED	QA
Brenda	Clane	Dong Jang
APPROVED BY CUSTOMER:		AVL Status
Please return one copy with approval to PSE-TW		

PSE Technology Corporation

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*RoHS Compliant

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E0-R-4-014 Rev. E

G83270022

VER. A 16-Jun-16

VERSION HISTORY

Version No.	Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
А	Jun.16,2016			Initial Release	
				_	
				_	
				_	

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ELECTRICAL SPECIFICATIONS

SRe Part Number: G83270022

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 10	ppm	at 25°C ± 5°C
Load Capacitance	CL	12.5	pF	Тур.
Drive Level	DL	0.1 / 0.5	μW	Typ. / Max.
Equivalent Series Resistance	ESR	70	ΚΩ	Max.
Temperature Coefficient	K	-0.03	ppm/°C ²	± 0.01ppm/°C ²
Operating Temperature Range	TR	-40 to 85	°C	
Shunt Capacitance	C0	1.5	pF	Тур.
Motional Capacitance	C1	6.5	fF	Тур.
Quality Factor	Q	13	K	Min.
Aging		± 3	ppm	Max. 1st year
Storage Temperature Range		-40 to 85	°C	
Insulation Resistance	_	500	ΜΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm
2	Shear test	Apply 20N(2.04kgf) static load to the core of quartz crystal units in the direction of the arrow using a R0.5 scratch tool, then hold for 5 seconds.	• Equivalent series resistance(E.S.R) change: Within 5kΩ
3	Core body strength	Apply 10N(1.02kgf) static load to the quartz crystal units center in the direction of the arrow using a R0.5 pushing tool, then hold for 10 seconds.	
4	Vibration	Frequency sweep method shall be applied as follows. Quartz crystal units shall be vibrated with the sweeping frequency from 10Hz to 55Hz and return to 10Hz in 1 minute, with 1.5mm amplitude. This vibration shall be applied for 2 hours in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-6.	
5	Shock	Quartz crystal units shall be accelerated at 9810m/s2 by 1ms pulse duration. This shock shall be applied 3 times in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-27.	

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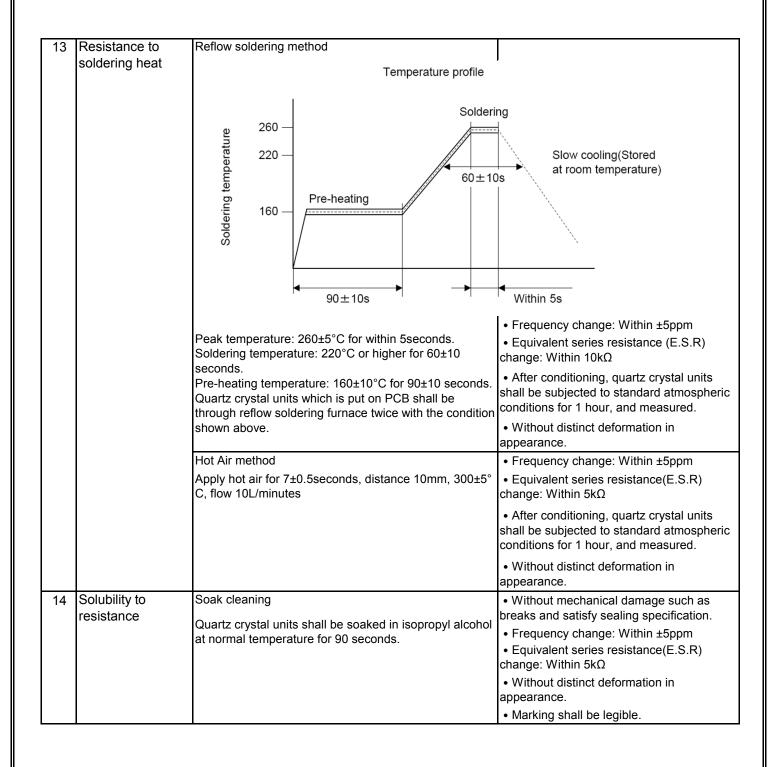
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6	Cold	atmosphe	Quartz crystal units shall be stored in the -40±3°C atmosphere for 1000 hours. Other procedures conform to JIS C 60068-2-1.			 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ
7	Dry heat	Quartz crystal units shall be stored in the 100±2°C atmosphere for 100 hours. Other procedures conform to JIS C 60068-2-2.			After conditioning, quartz crystal units o shall be subjected to standard atmospheric conditions for 1 hour, and measured.	
8	Damp heat	Quartz crystal units shall be stored in the 40±2℃ atmosphere with 90 to 95% relative humidity for 1000 hours. Other procedures conform to JIS C 60068-2-3.				
9	Change of temperature	Quartz crystal units shall be subjected successively 100 cycles of temperature change shown below. Other procedures conform to JIS C 0025.				0
		1 2 3 4	Temperatu -40±3°C Normal temper 100±2°C Normal temper	ature	Duration 30min. Within 30 sec. 30min. Within 30 sec.	
10	Sealing	Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes. Quartz crystal units shall be tested by Mass		Without repetitive leaking bubbles from quartz crystal units. 1×10-9 Pa·m3/s or less		
11	Aging	spectrometric leakage detector to measure the leakage rate of helium gas. Quartz crystal units shall be stored in the 85±3°C atmosphere for 720±12 hours.			Frequency change: Within ±5ppm Equivalent series resistance(E.S.R)	
				 change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. 		
12	Solder-ability		coated with flux th for 3.5±0.5 sec		e immersed in the	Minimum 95% of immersed terminal shall be covered with new uniform solder.
			Items		Conditions	
	1		Solder	Sn-3.	0Ag-0.5Cu	
			+	_	oximately 25wt%	
		2	Flux	metha	anol(JIS K 8891) on of resin(JIS K	

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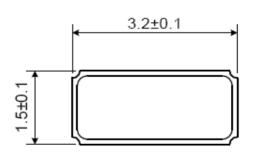
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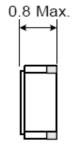
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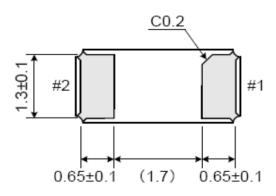
Marking



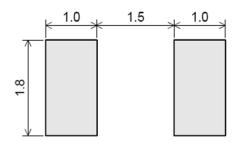
Dimensions (Units: mm)



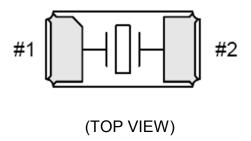




Recommended Soldering Pattern



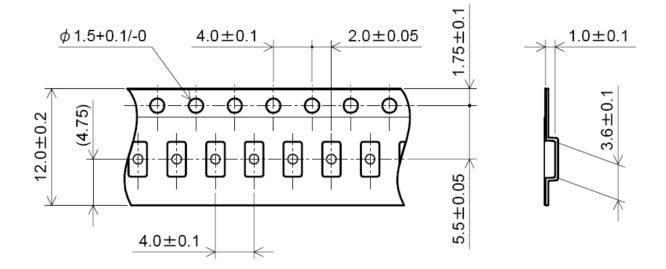
Internal connection



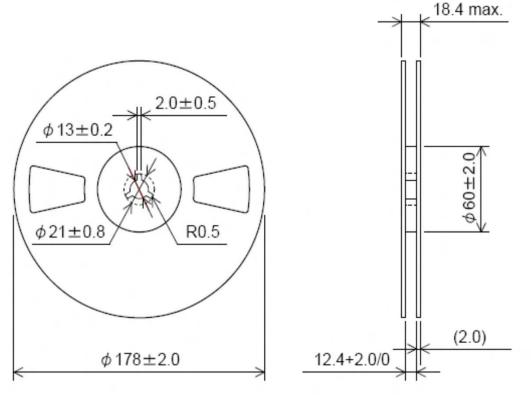
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TAPING (Units: mm)



REEL (Units: mm)



Quantity: 3000pcs / Reel

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